Very Efficient Yield Estimation of the **Microwave Performance of Very High-Accuracy Machined Parts**

Werner Steyn

Department of Electrical and Electronic Engineering Stellenbosch University South Africa



Stellenbosch

Overview



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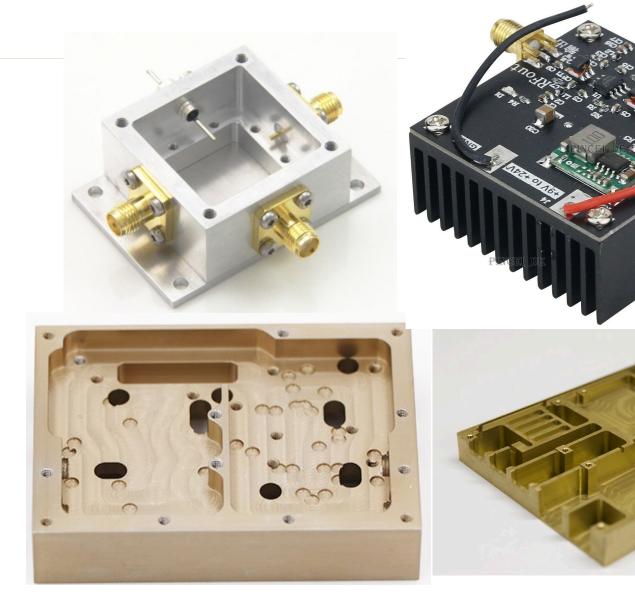
• What is the problem?

• How can we improve that?

• Example

• Future

What is the problem?





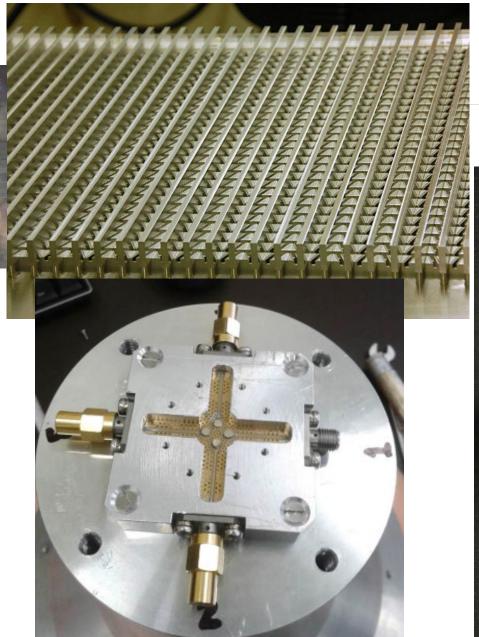


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What is the problem?





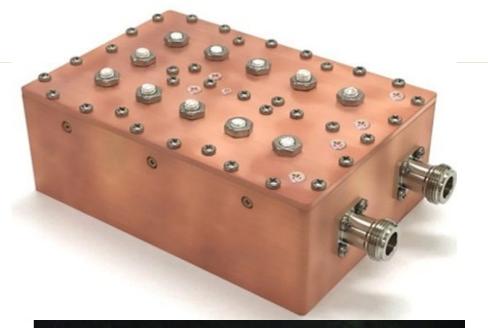


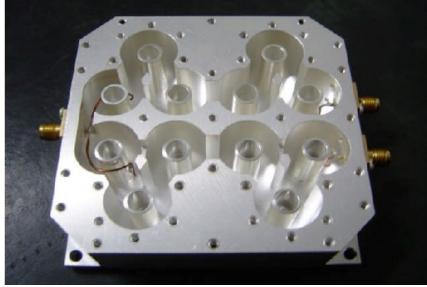


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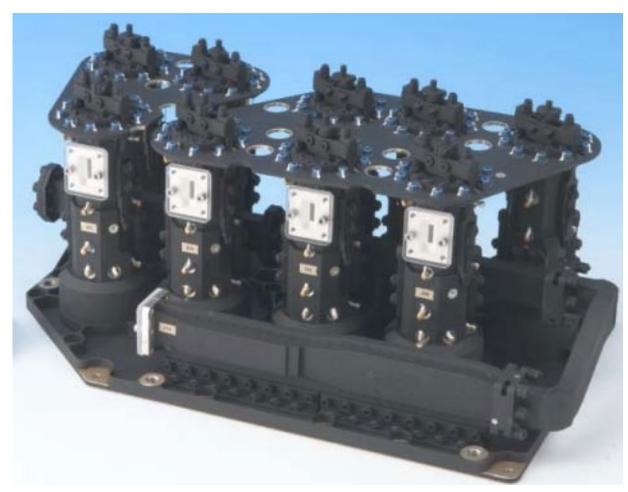
What is the problem?







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Normal design procedure - with tuning



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3D solver	 Decide on filter topology
	 Calculate initial dimensions
x 1	Combine elements - assume 0% tolerance
xn	 Fine tuning by hand
XN	 Optimization process
xn	 Add tuning elements

Design procedure - no tuning



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3D solver	 Decide on filter topology
	Calculate initial dimensions
x 1	Combine elements - assume 0% tolerance
xn	 Fine tuning by hand
XN	 Optimization process
x NN	 Yield analysis – Monte Carlo

How can we improve that?



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• Polynomial Chaos Expansion (PCE)

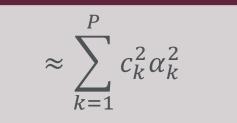
Surrogate modelling technique that represents a **system performance parameter** in terms of orthogonal polynomial expansions of **random system parameters**

$$\widehat{y}(x) = \sum_{k=0}^{N} c_k \phi_{\overline{k}}(x)$$

Mean Estimation

 $\approx c_0 \alpha_0$





Yield Estimation

Only requires Mean and Variance

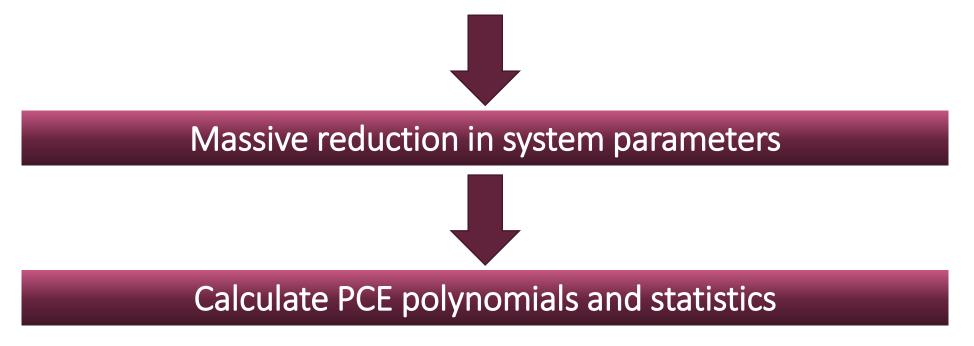
How can we improve that?



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• Non-Linear Partial-Least-Squares (NLPLS)

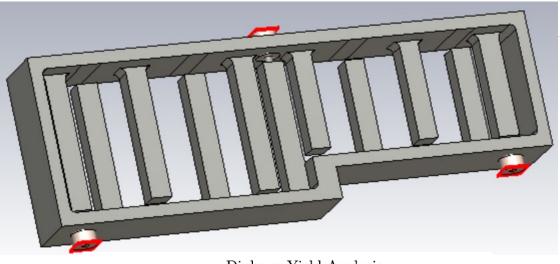
is a meta-modelling method that attempts to find relations between observable system parameters and **latent variables** (inferred variables)



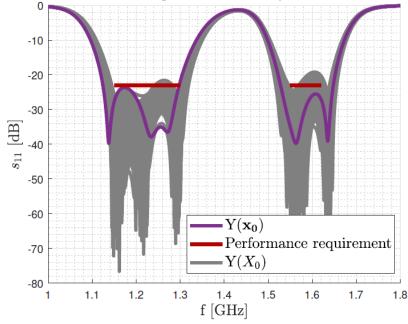
Example: L-band Diplexer 37 parameters

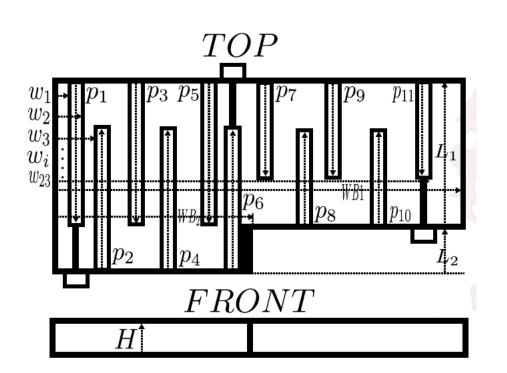


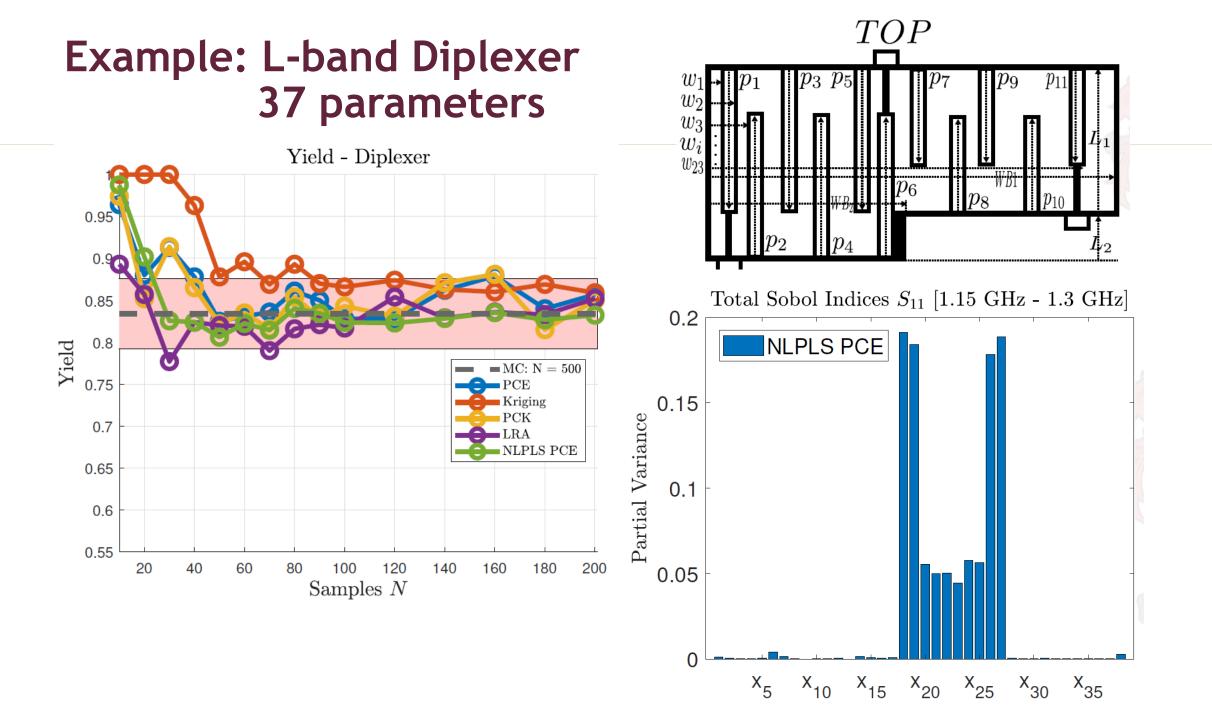
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Diplexer Yield Analysis



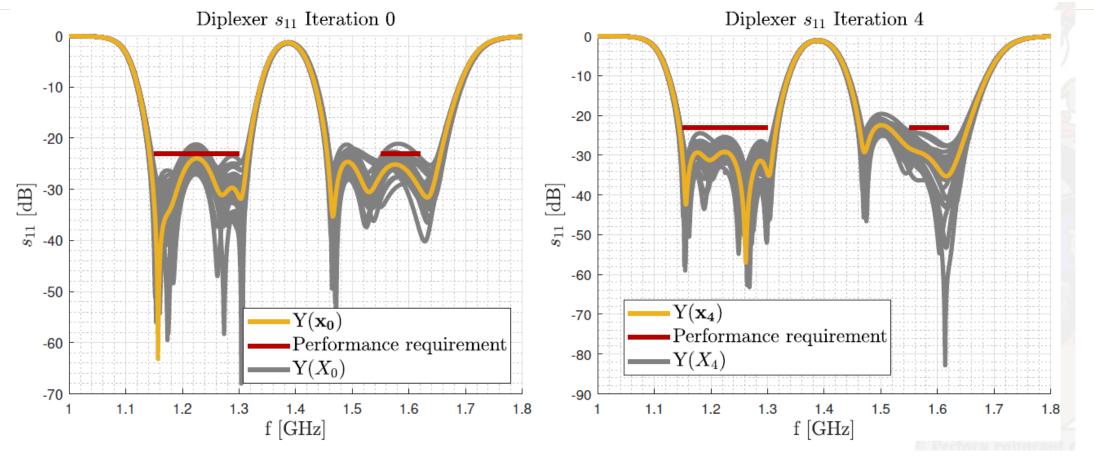




Future: Optimization for Yield

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100% yield after 5 iterations – less than 200 3D Solver runs!

The End



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Thank you for your attention